



4/17/2012

RELIABILITY MONITOR REPORT
FOR

MFN Complementary BiCMOS (CB50)

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

This Report was prepared by
Maxim Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX3643ETG+	MAX3646ETG+
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The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 3274 QUANTITY: 80 FAILS: 0 FITS: 34.9

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between and

Process Information:

Process Description: MFN Complementary BiCMOS (CB50)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1113	MAX3643ETG+	135C	192 HRS	48	0	J0UZB4001BQ
HIGH TEMP OP LIFE	1113	MAX3643ETG+	135C	240 HRS	32	0	J0UZB4001CQ
Total:						0	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1152	MAX3646ETG+	-65C TO 150C	200 CYS	77	0	JJR0J3056BC
TEMP CYCLE, 5' RAMP, 10' DWELL	1152	MAX3646ETG+	-65C TO 150C	200 CYS	77	0	JJR0J3056BA
Total:						0	

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